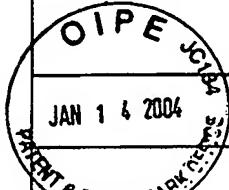


LIST OF REFERENCES CITED BY APPLICANT Form PTO-1449 (Use several sheets if necessary)				ATTY. DOCKET NO.: 4717-11300		APPLICATION NO.:	
				APPLICANT: Claire RICHTARCH			
				FILING DATE: September 25, 2003		GROUP:	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	*CITE AS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
WLL	AA	5,895,583	4/1999	Augustine et al.	216	53	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES    NO
WLL	AB	0 966 034	12/1999	EPO			X
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
WLL	AC	Bruel, M. et al., "Smart-Cut": A Promising New SOI Material Technology, IEEE SOI Conference, October 1995, pp 178-179.					
WLL	AD	Maleville et al., "Wafer Bonding and H-Implantation Mechanisms Involved In The Smart-Cut Technology", Materials Science and Engineering, 1997, pp. 14-19.					
EXAMINER <i>Walter J. Tavelly Jr.</i>		2/9/05					
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							
A M							

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<b>LIST OF REFERENCES CITED BY APPLICANT</b> <b>Form PTO-1449</b> <i>(Use several sheets if necessary)</i>				ATTY. DOCKET NO.:	APPLICATION NO.:		
				4717-11300	10/671,812		
				APPLICANT:			
				Claire RICHTARCH			
 JAN 14 2004				FILING DATE:	GROUP:		
				September 25, 2003	1762		
<b>U.S. PATENT DOCUMENTS</b>							
*EXAMINE R INITIAL	CITE NO.	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AA							
AB							
AC							
AD							

**FOREIGN PATENT DOCUMENTS**

AE

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
WL	AE	FR 02-09869	8/2000	France	—	—	X	
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WL	AH	A. J. Auberton-Hervé et al., "Why Can SMART-CUT® Change the Future of Microelectronics?", International Journal of High Speed Electronics and Systems, Vol. 10, no. 1, 2000, pp 131-146.
WL	AI	"Thermal and Dopant Processes", Chapter 4, Advanced Semiconductor Fabrication Handbook, ICE, 1998
	AJ	
	AK	

**EXAMINER**


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